Advanced Architectures for Hybrid Edge Analytics Models on Adaptive Smart Areas

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Message from the Guest Editors

Special Issue Information

Dear Colleagues,

IoT and machine learning are two of the most exciting disciplines in technology today because of their profound impact on both businesses and individuals.

The focus of most of these applications is to gather information from the environment and transmit it over the Internet to powerful remote servers where intelligence and decision making resides. However, applications such as self-driving cars are critical and require accurate real-time responses.

To alleviate some of the above problems, edge computing has emerged, changing the way data is processed, improving response times, and addressing the connectivity, scalability, and security issues inherent to remote servers. Hybrid approaches have also emerged, with the goal of maximizing the benefits of edge and cloud.

This Special Issue invites researchers to submit original quality studies regarding the technologies in the domains of IoT and machine learning, as well as their integration in hybrid architectures, and urges them to address the main subdisciplines.

Special Issue

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Message from the Editor-in-Chief

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